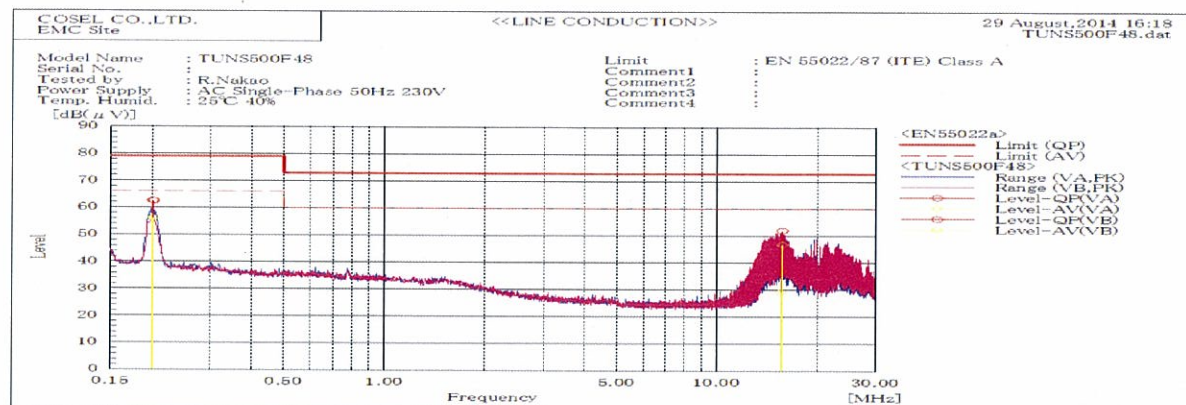
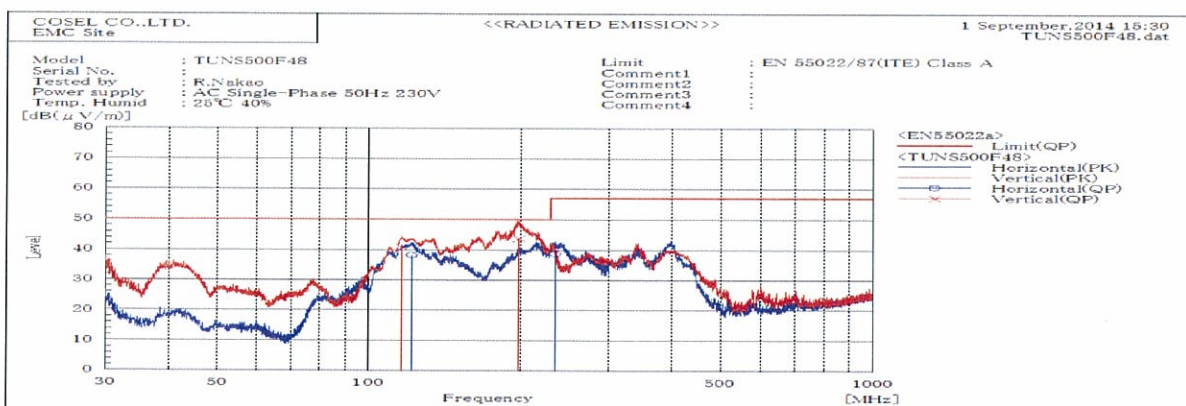


DATA SHEET		Date	14-Sep-14
Model	TUNS500F48	Temp.	25 degreeC
Test	EMI	Humid.	40 %RH
	Line conduction & Radiated emission	Tested by	R.Nakao



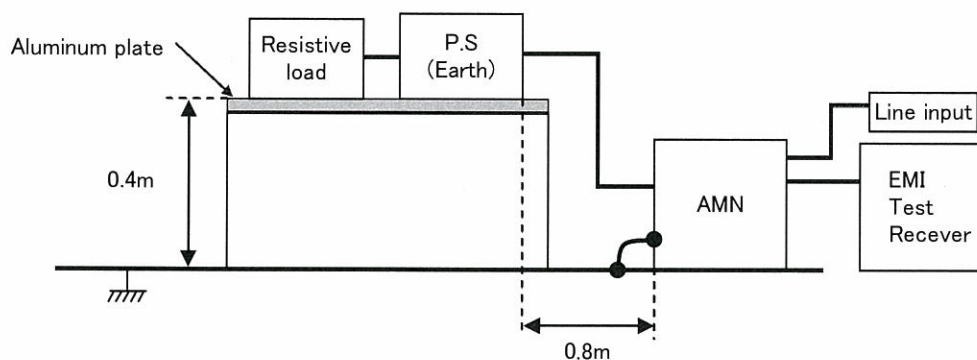
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.20211		VA	42.3	35.9	20.2	62.5	56.1	79.0	66.0	16.5	9.9	Pass	
0.20043		VB	42.4	36.0	20.2	62.6	56.2	79.0	66.0	16.4	9.8	Pass	
15.561		VA	16.1	8.2	21.1	37.2	29.3	73.0	60.0	35.8	30.7	Pass	
15.7141		VB	31.0	25.8	21.1	52.1	46.9	73.0	60.0	20.9	13.1	Pass	



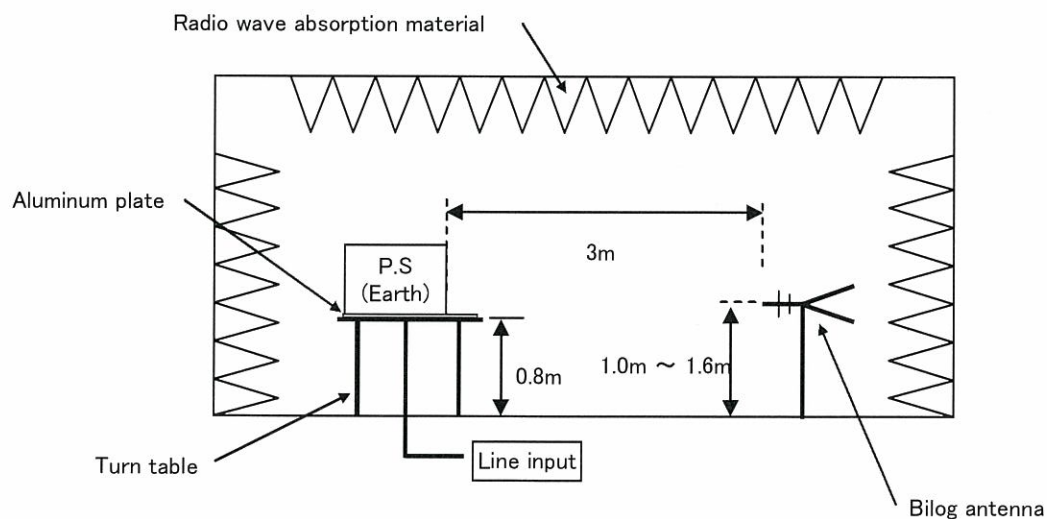
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
115.852	V	Stable	58.6	-17.7		40.9		50.0	9.1	Pass	125	100	
121.425	H	Stable	57.5	-19.3		38.2		50.0	11.8	Pass	158	316	
197.935	V	Stable	59.4	-15.7		43.7		50.0	6.3	Pass	108	0	
234.417	H	Stable	57.8	-19.1		38.7		57.0	18.3	Pass	130	56	

DATA SHEET		Date	14-Sep-14
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Nakao

1. Line conduction



2. Radiated emission



Test: EMI

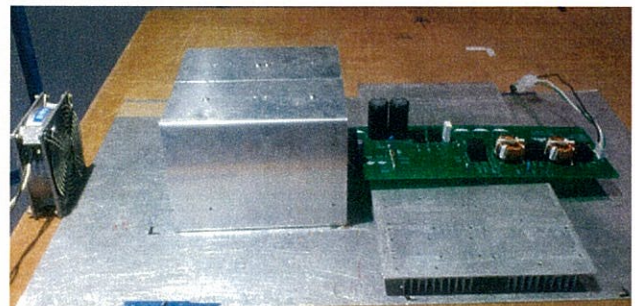
Model Name: TUNS500F Series

○ Photographs of Test Set-Up

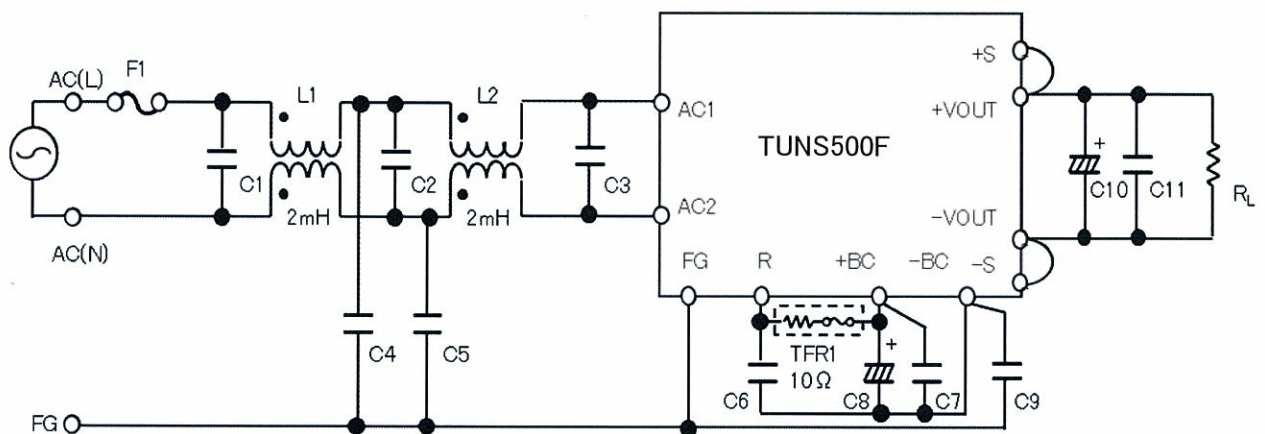
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- L1, L2 : SC-15-200(NEC TOKIN)
- C1, C2 : 0.68 μ F 310V Film Capacitor \times 2
- C3 : 1.0 μ F 310V Film Capacitor \times 2
- C4, C5, C9 : 2200pF Ceramic Capacitor
- C6, C7 : 0.68 μ F 450V Film Capacitor \times 2
- C8 : 390 μ F 450V Electrolytic Capacitor \times 2
- C10 : TUNS500F12 2200 μ F 25V Electrolytic Capacitor
- TUNS500F28 1000 μ F 50V Electrolytic Capacitor
- TUNS500F48 470 μ F 63V Electrolytic Capacitor

- C11 : TUNS500F12 10 μ F Ceramic Capacitor
- TUNS500F28 4.7 μ F Ceramic Capacitor
- TUNS500F48 2.2 μ F Ceramic Capacitor